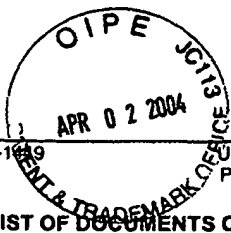


Sheet 1 of 2

FORM PTO-149 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-987	SERIAL NO. 09/869,274			
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT A. NISHIMURA et al				
		FILING DATE June 26, 2001	GROUP			
U.S. PATENT DOCUMENTS						
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA 6,030,890	2/29/00	Iwabuchi			
	AB 6,008,543	12/28/99	Iwabuchi			
	AC 9,334,940	9/10/96	Hubacher			
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
FOREIGN PATENT DOCUMENTS						
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OC	AL 4-26537	3/3/92	Japan			<input type="checkbox"/> <input type="checkbox"/>
OC	AM 4-96343	3/27/92	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN 5-218042	8/27/93	Japan			<input type="checkbox"/> <input type="checkbox"/>
OC	AO 8-250498	9/27/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AP 8-64633	3/8/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
	AR	IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.				
	AS					
	AT					
EXAMINER	Old Chandra			DATE CONSIDERED August 25, 2004		



FORM PTO-159 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO. 09/869,274	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al			
				FILING DATE June 26, 2001		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AL	8-340029	12/24/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	OC AM	8-29451	2/2/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AR						
	AS						
	AT						
EXAMINER <i>Olaf Chomhura</i>				DATE CONSIDERED <i>August 25, 2004</i>			